

**● PRINTER RUSH ●**  
**(PTO ASSISTANCE)**

Application : <u>10/627,638</u>	Examiner : <u>D. Williams</u>	GAU : <u>2878</u>
From: <u>S. Winslow</u>	Location: <u>IDC</u> FMF FDC	Date: <u>10-20-05</u>
Tracking #: <u>EPM 10/627,638</u> Week Date: <u>8-1-05</u>		

DOC CODE	DOC DATE	MISCELLANEOUS
<input type="checkbox"/> 1449		<input type="checkbox"/> Continuing Data
<input type="checkbox"/> IDS		<input type="checkbox"/> Foreign Priority
<input checked="" type="checkbox"/> CLM	<u>7-28-03</u>	<input type="checkbox"/> Document Legibility
<input type="checkbox"/> IIFW		<input type="checkbox"/> Fees
<input type="checkbox"/> SRFW		<input type="checkbox"/> Other
<input type="checkbox"/> DRW		
<input type="checkbox"/> OATH		
<input type="checkbox"/> 312		
<input type="checkbox"/> SPEC		

<b>[RUSH] MESSAGE:</b>	<u>Claim 18 does not end with a period.</u>
          <div style="text-align: right;"><u>Please advise</u></div> <div style="text-align: right;"><u>Thanks</u></div>	

<b>[XRUSH] RESPONSE:</b>	<u>Corrected</u>
          <div style="text-align: right;"><b>INITIALS:</b> <u>JBH</u></div>	

NOTE: This form will be included as part of the official USPTO record, with the Response document coded as XRUSH.  
REV 10/04

(d) adjusting the optical energy values as a function of the first and second dark current values.

15. A method for correcting for wavefront aberrations in a lithography system having a wafer stage comprising:

scanning a charge coupled device having first and second arrays of devices located on the wafer stage;

determining a first dark current value from the first and second array of devices;

generating optical energy values from light having the wavefront aberrations received at the first array of devices;

determining a second dark current value from the second array of devices;

adjusting the optical energy values as a function of on the first and second dark current values; and

generating control signals on the adjusted optical energy values that are used to control an optical device in the lithography system to compensate for the wavefront aberrations.

16. The method of claim 15, further comprising providing the second array of devices that are non-sensitive to the light.

17. The method of claim 15, further comprising determining the second dark current value at substantially a same time as the optical energy is generated.

18. The method of claim 15, further comprising performing the generating step during scanning of the CCD .

19. The method of claim 15, further comprising using full-frame architecture technology, interline architecture technology, or frame-transfer

JBH  
10-21-05